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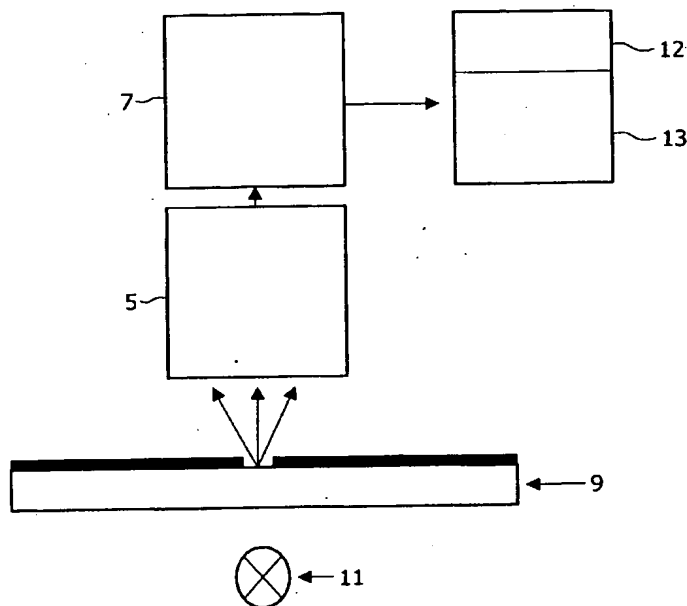
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[Continued on next page]

(54) Title: MASK INSPECTION APPARATUS AND METHOD



(57) Abstract: Apparatus for optical inspection of an object, comprising: an optical imaging system for generating an actual image of the real object, a calculation unit for calculating an estimated image of an object of desired shape in respect of a known aberration coefficient of the optical imaging system, an image analysis unit for detecting differences between the actual image and the image calculated by the calculation unit.

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